

AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions and listings of claims in the application:

1. (Previously Presented) A method comprising:

 monitoring one or more sensor outputs measuring a power consumption property of a chip; and

 recording a time that at least one of the sensor outputs indicates an existence of the power consumption property at a predetermined value.
2. (Original) The method of claim 1, wherein the power consumption property of the chip comprises temperature, and the temperature comprises a temperature range including one or more temperatures.
3. (Original) The method of claim 2, wherein each sensor output corresponds to a temperature range, and indicates the existence of the one or more temperatures measured at the corresponding sensor output.
4. (Original) The method of claim 1, wherein the power consumption property of the chip comprises voltage drop, and the voltage drop range includes one or more voltage drops.
5. (Original) The method of claim 4, wherein each sensor output corresponds to a voltage drop range, and each sensor output indicates the existence of a voltage drop measured at the corresponding output.

6. (Previously Presented) A method for analyzing operation of a chip executing an application, comprising:

monitoring one or more parts of the application by a sensor attached to the chip;

obtaining event data from the sensor, the event data including times that one or more sensor outputs indicates an existence of a power consumption property of the chip at a predetermined value; and

for at least one of the parts of the application, correlating the event data with the parts of the application.

7. (Original) The method of claim 6, wherein the power consumption property comprises temperature.

8. (Original) The method of claim 6, wherein the power consumption property comprises voltage drop.

9. (Previously Presented) An apparatus for analyzing operation of a chip executing an application, comprising:

circuitry capable of:

monitoring one or more parts of the application by a sensor attached to the chip;

obtaining event data from the sensor, the event data including times that one or more sensor outputs indicates an existence of a power consumption property of the chip at a predetermined value; and

for at least one of the parts of the application, correlating the event data with the parts of the application.

10. (Original) The apparatus of claim 9, wherein the power consumption property of the chip comprises temperature, and the temperature comprises a temperature range including one or more temperatures.
11. (Original) The apparatus of claim 10, wherein each sensor output corresponds to a temperature range, and indicates the existence of the one or more temperatures measured at the corresponding sensor output.
12. (Original) The apparatus of claim 9, wherein the power consumption property of the chip comprises voltage drop, and the voltage drop comprises a voltage drop range including one or more voltage drops.
13. (Original) The apparatus of claim 12, wherein each sensor output corresponds to a voltage drop range, and each sensor output indicates the existence of a voltage drop measured at the corresponding output.
14. (Previously Presented) A system for analyzing operation of a chip executing an application, comprising:
 - circuitry on a first node, the circuitry connected to the chip and capable of:
 - monitoring one or more parts of the application by a sensor attached to the chip;
 - obtaining event data from the sensor, the event data including times that each of one or more sensor outputs indicates an

existence of a power consumption property of the chip at a predetermined value; and

for at least one of the parts of the application, correlating the event data with the parts of the application; and

a performance analyzer on a second node, the performance analyzer communicatively coupled to the circuitry on the first node to use the correlated information.

15. (Previously Presented) The system of claim 14, wherein the power consumption property of the chip comprises temperature, and the temperature comprises a temperature range including one or more temperatures.
16. (Original) The system of claim 15, wherein each sensor output corresponds to a temperature range, and indicates the existence of the one or more temperatures measured at the corresponding sensor output.
17. (Original) The system of claim 14, wherein the power consumption property of the chip comprises voltage drop, and wherein the voltage drop range includes one or more voltage drops.
18. (Original) The system of claim 17, wherein each sensor output corresponds to a voltage drop range, and each sensor output indicates the existence of a voltage drop measured at the corresponding output.
19. (Previously Presented) An article comprising a machine-readable medium having machine-accessible instructions, the instructions when executed by a machine, result in the following:

monitoring one or more parts of the instructions by a sensor attached to the machine;

obtaining event data from the sensor, the event data including times that each of one or more sensor outputs indicates an existence of a power consumption property of a chip at a predetermined value; and

for at least one of the parts of the instructions, correlating the event data with the parts of the instructions.

20. (Original) The article of claim 19, wherein the power consumption property of the chip comprises a temperature range, and wherein the temperature range includes one or more temperatures.
21. (Original) The article of claim 20, wherein each sensor output corresponds to a temperature range, and indicates the existence of the one or more temperatures measured at the corresponding sensor output.
22. (Original) The article of claim 19, wherein the power consumption property of the chip comprises voltage drop range, and wherein the voltage drop range includes one or more voltage drops.
23. (Original) The article of claim 22, wherein each sensor output corresponds to a voltage drop range, and each sensor output indicates the existence of a voltage drop measured at the corresponding output.